

# Search Notes



Application/Control No.

10/517,090

Examiner

Sam K. Ahn

Applicant(s)/Patent under  
Reexamination

TSATSANIS ET AL.

Art Unit

2611

## SEARCHED

Class	Subclass	Date	Examiner
375	219, 222, 257, 296, 343, 346	12/4	<i>a</i>
398	193		
455	114.3, 557		
700	53	12/11	<i>am</i>

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
<i>EAST inventor search keyword and citation search IEEE and google keyword and citation search</i>	12/4	<i>a</i>
<i>consulted Young-Tee 375 P.E.</i>	12/11	<i>am</i>